

650V GaN HEMT

Description

The CC65H270DNGI Series 650V, 270mΩ gallium nitride (GaN) FETs are normally-off devices.

Classicchip GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic onresistance, delivering significant advantages over traditional silicon (Si) devices.

Classicchip is a leading-edge wide band gap supplier with world-class innovation .

Automotive

-  Adapter
-  Renewable energy
-  Telecom and data-com
-  Servo motors
-  Industrial
-  Automotive

General Features

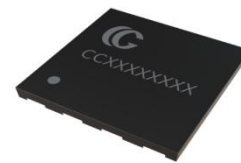
- Easy to drive —compatible with standard gate drivers
- Low conduction and switching losses
- RoHS compliant and Halogen-free

Benefits

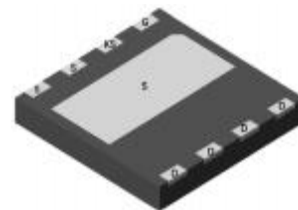
- Increased efficiency through fast switching
- Increased power density
- Reduced system size and weight

Ordering Information

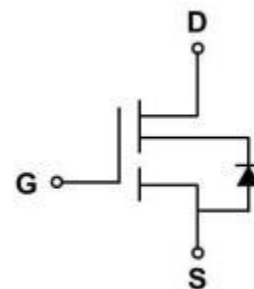
Part Number	Package	Package Configuration
CC65H270DNGI	DFN 8*8	Source



Top



Bottom



Circuit Symbol

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	270mΩ	7.9A	7.8nC

Absolute Maximum Ratings

$T_C=25^{\circ}\text{C}$ unless otherwise stated

Symbol	Parameter		Limit value	Unit
V_{DSS}	Drain to source voltage ($T_J = -55^{\circ}\text{C}$ to 150°C)		650	V
$V_{(TR)DSS}$	Drain to source voltage-transient ^a		800	
V_{GSS}	Gate to source voltage		-20~+20	
I_D	Continuous drain current @ $T_C=25^{\circ}\text{C}$ ^b		7.9	A
	Continuous drain current @ $T_C=125^{\circ}\text{C}$ ^b		3.5	
I_{DM}	Pulse drain current (pulse width: 100 μs)		14	A
P_D	Maximum power dissipation @ $T_C=25^{\circ}\text{C}$		32	W
T_C	Operating temperature	Case	-55~150	$^{\circ}\text{C}$
T_J		Junction	-55~150	$^{\circ}\text{C}$
T_S		Storage temperature	-55~150	$^{\circ}\text{C}$

a. In off-state, spike duty cycle $D<0.01$, spike duration $<1\mu\text{s}$

b. For increased stability at high current operation

Thermal Resistance

Sym bo l	Paramete r	Limit value	Unit
$R_{\theta JC}$	J unctio n - to - case	3.9	° C /W

Electrical Parameters

$T_J=25.0$ °C unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
$V_{(BL)DSS}$	Drain-source voltage	650	-	-	V	$V_{GS}=0V$
$V_{GS(th)}$	Gate threshold voltage	-	1.7	-	V	
$\Delta V_{GS(th)}/T_J$	Gate threshold voltage temperature coefficient	-	-6.8	-	mV/°C	$V_{DS}=1V, I_{DS}=1mA$
$R_{DS(on)}$	Drain-source on-resistance	-	270	320	mΩ	$V_{GS}=10V, I_D=1A, T_J=25.0$ °C
		-	570	-		$V_{GS}=10V, I_D=1A, T_J=150.0$ °C
I_{DSS}	Drain-to-source leakage current	-	-	10	μA	$V_{DS}=650V, V_{GS}=0V, T_J=25.0$ °C
		-	-	100		$V_{DS}=650V, V_{GS}=0V, T_J=150.0$ °C
I_{GSS}	Gate-to-source forward leakage current	-	-	±100	nA	$V_{GS}=±20V$
C_{ISS}	Input capacitance	-	378	-	pF	$V_{GS}=0V, V_{DS}=400V, f=1MHz$
C_{OSS}	Output capacitance	-	23	-		
C_{RSS}	Reverse capacitance	-	0.97	-		
Q_G	Total gate charge	-	7.8	-	nC	$V_{DS}=400V, V_{GS}=0V$ to 10V, $I_D=1A$
Q_{GS}	Gate-source charge	-	1.1	-		
Q_{GD}	Gate-drain charge	-	1.8	-		
Q_{OSS}	Output charge	-	36	-	nC	$V_{GS}=0V, V_{DS}=0V$ to 400V, $f=1MHz$
$t_{D(on)}$	Turn-on delay	-	2.5	-	ns	$V_{DS}=400V, V_{GS}=0V$ to 10V, $I_D=2.1A$, $R_{G-on(ext)}=6.8Ω, R_{G-off(ext)}=2.2Ω$, $L=250μH$
t_R	Rise time	-	7	-		
$t_{D(off)}$	Turn-off delay	-	9.7	-		
t_F	Fall time	-	28	-		

Electrical Parameters

$T_J=25^{\circ}\text{C}$ unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V_{SD}	Source - Drain reverse voltage	-	2.2	-	V	$V_{GS}=0\text{V}$, $I_{SD}=5\text{A}$
t_{RR}	Reverse recovery time	-	13	-	ns	$I_F=5\text{A}$, $V_{DD}=400\text{V}$, $dI_F/dt=165\text{A}/\mu\text{s}$
Q_{RR}	Reverse recovery charge	-	3.2	-	nC	

Typical Characteristics

$T_J=25^{\circ}\text{C}$ unless otherwise stated

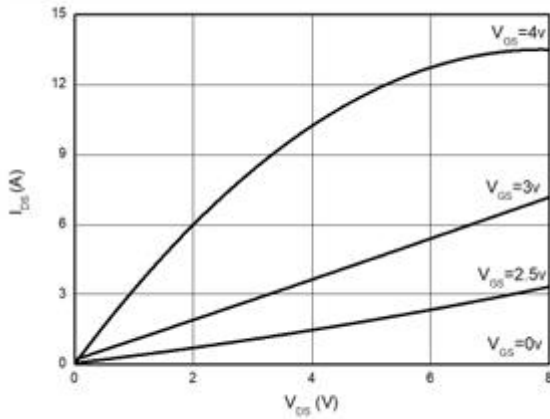


Figure 1. Typical Output Characteristics $T_J=25^{\circ}\text{C}$

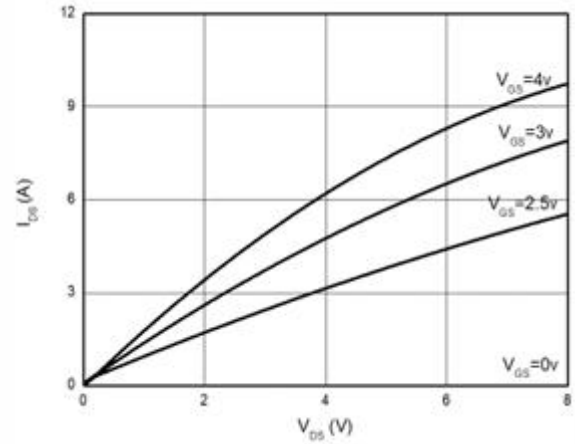


Figure 2. Typical Output Characteristics $T_J=125^{\circ}\text{C}$

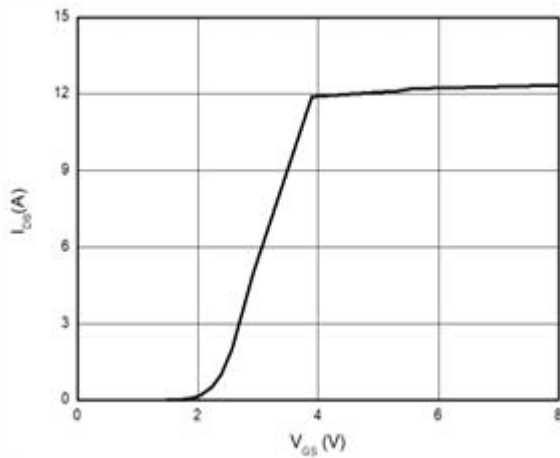


Figure 3. Typical Transfer Characteristics ($V_{DS}=5V$)

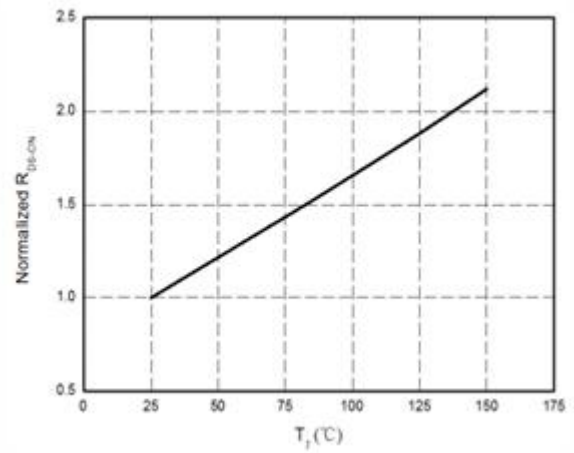


Figure 4. Normalized On-resistance

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

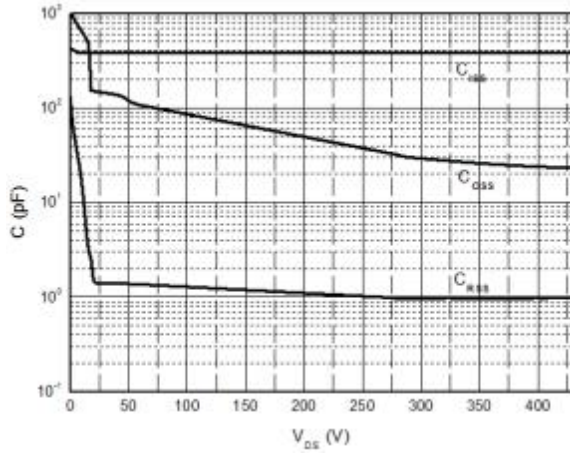


Figure 5. Typical Capacitance ($f=1\text{MHz}$)

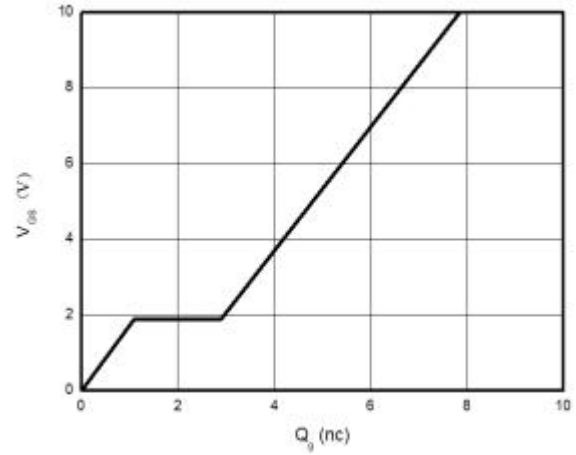


Figure 6. Typical Gate Charge ($V_{DS}=400\text{V}$, $I_D=1\text{A}$)

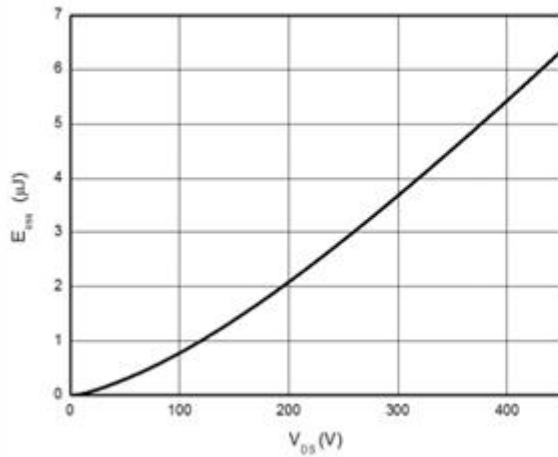


Figure 7. Typical C_{oss} Stored Energy

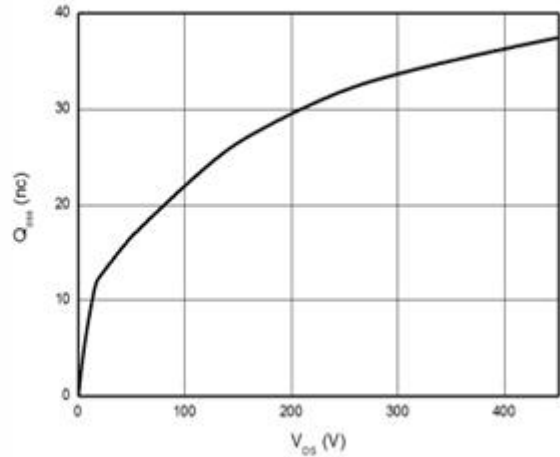


Figure 8. Typical Q_{oss}

Typical Characteristics

$T_J = 25^\circ\text{C}$, C unless otherwise stated

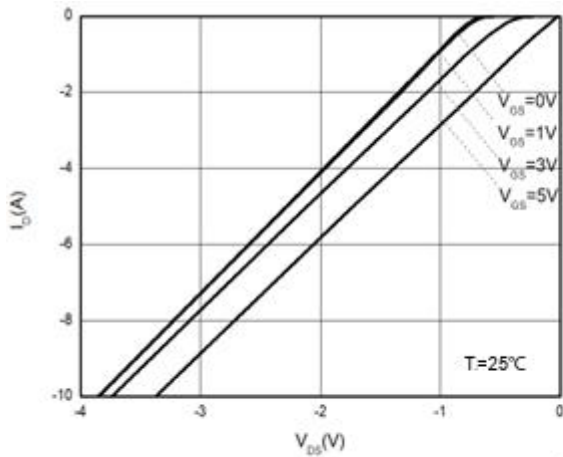


Figure 9. Channel Reverse Characteristics $T_J = 25^\circ\text{C}$

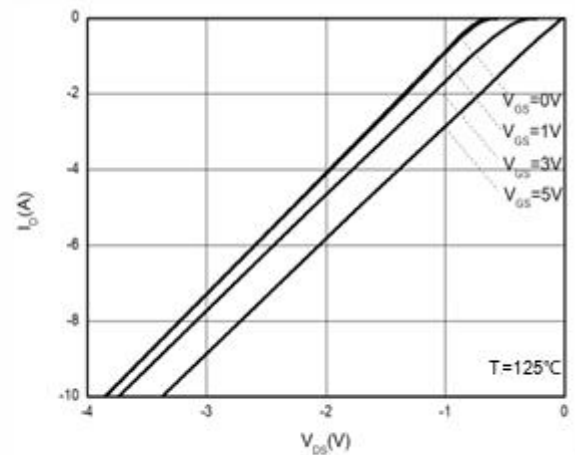


Figure 10 Channel Reverse Characteristics $T_J = 125^\circ\text{C}$

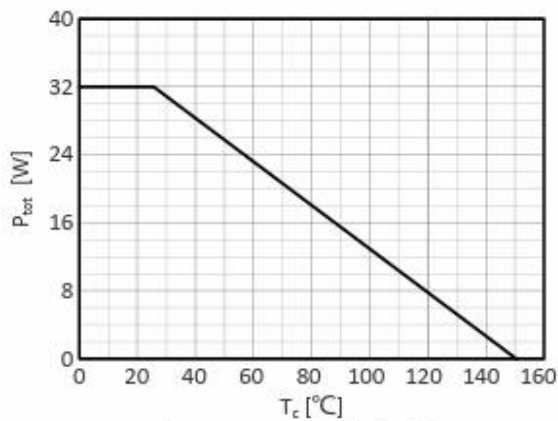


Figure 11. Power Dissipation

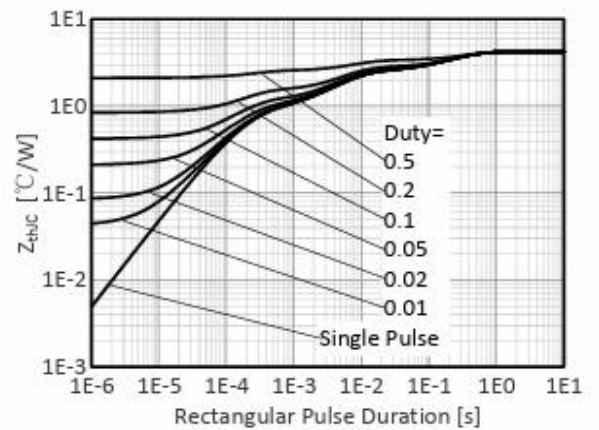


Figure 12. Transient Thermal Resistance

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

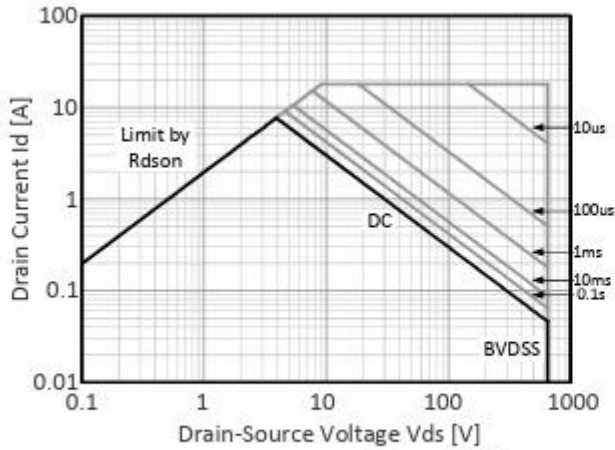


Figure 13. Safe Operating Area $T_c=25^\circ\text{C}$

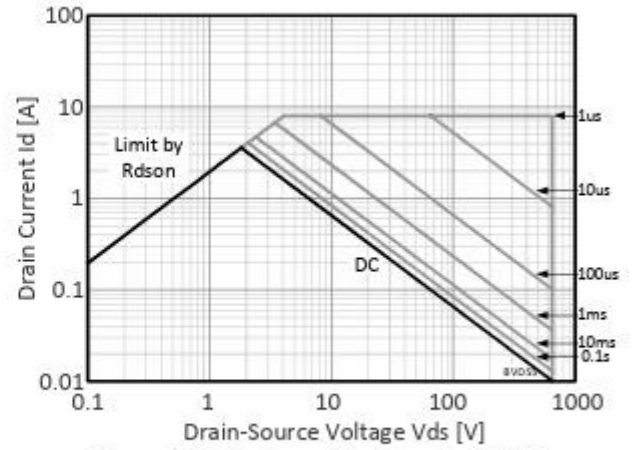


Figure 14. Safe Operating Area $T_c=125^\circ\text{C}$

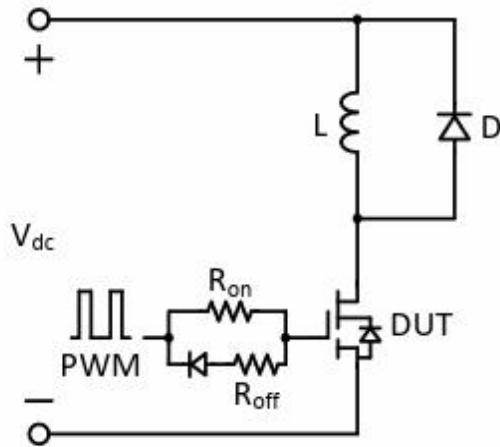


Figure 15. Switching times with inductive load

$V_{DS}=400\text{V}$, $V_{GS}=0\text{V to }10\text{V}$, $I_D=2.1\text{A}$,
 $R_{G-on(ext)}=6.8\Omega$, $R_{G-off(ext)}=2.2\Omega$, $L=250\mu\text{H}$

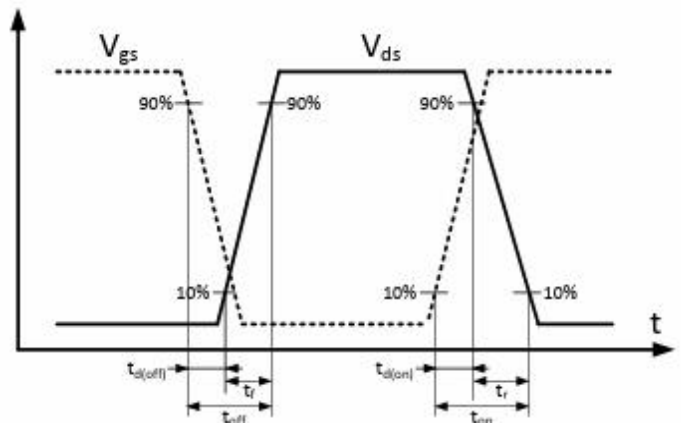
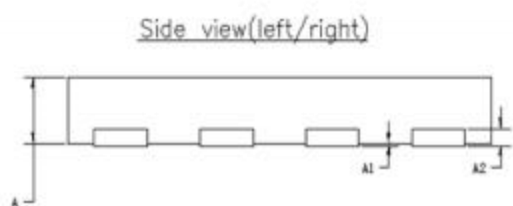
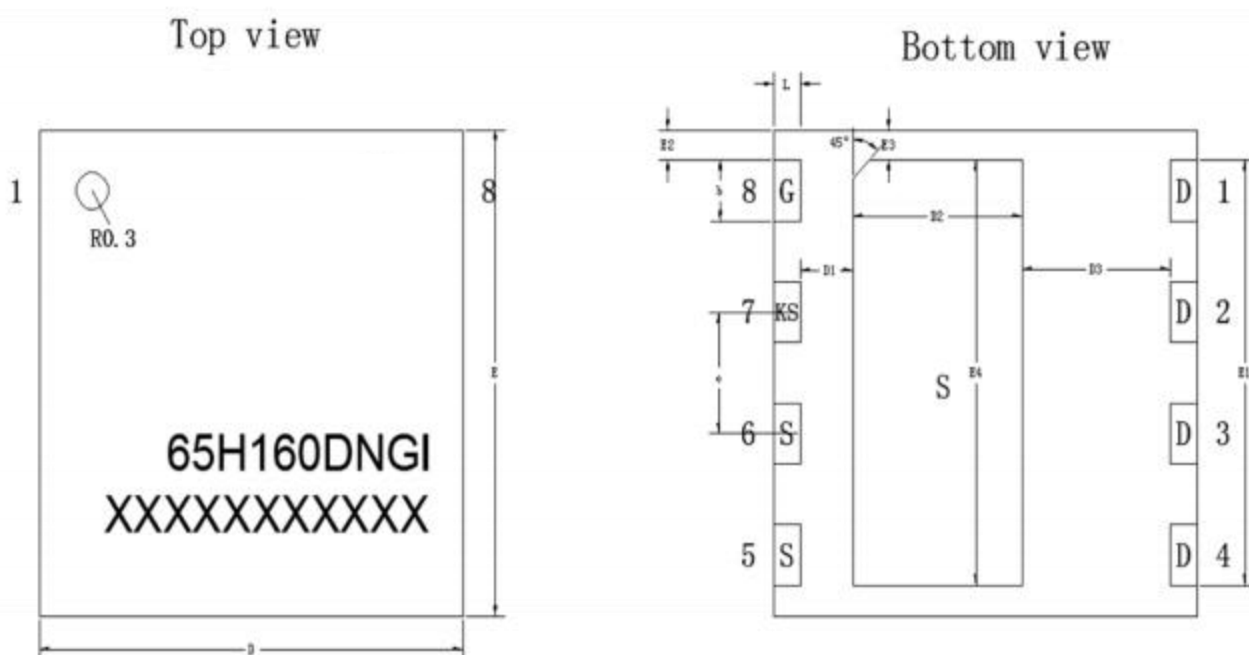


Figure 16. Switching times with waveform

PACKAGE DIMENSIONS

DFN8x8-8L-1.10-A



Symbol	Min. (mm)	Mean. (mm)	Max. (mm)
A	1.05	1.10	1.15
A1	0	0.02	0.05
A2	0.203REF		
D	7.9	8	8.1
E	7.9	8	8.1
D1	0.9	1	1.1
D2	3.1	3.2	3.3
D3	2.7	2.8	2.9
E1	6.9	7	7.1
E2	0.4	0.5	0.6
E3	0.4	0.5	0.6
E4	6.9	7	7.1
e	1.9	2	2.1
b	0.9	1	1.1
L	0.4	0.5	0.6